

2/26/2004

FORM PTO-1449 (modified)
To: U.S. Department of Commerce
(PW FORM PAT-1449)
Patent and Trademark Office

Atty.
Dkt. No.

M#

Client Ref.

308089

P-01500.010-US

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: FLAGELLO et al.

Continuation-In-Part of Appln. No.: 10/374,509 filed
February 27, 2003 10/786, 473

Filing Date: February 26, 2004

Date: February 26, 2004

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Examiner: Unassigned

Group Art Unit: Unassigned

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
PA	AR 3,998,524	12/1976	HUBBY, Jr. et al.			
PA	BR 4,384,760	05/1983	ALFERNES			
PA	CR 5,383,053	01/1995	HEGG et al.			
PA	DR 6,288,840	09/2001	PERKINS et al.			
PA	ER 6,392,800	05/2002	SCHUSTER			
PA	FR 6,452,724	09/2002	HANSEN et al.			
PA	GR 6,122,103	09/2000	PERKINS et al.			
PA	HR 6,191,880 B1	02/2001	SCHUSTER			
PA	IR 5,523,193	06/1996	NELSON			
PA	JR 5,296,891	03/1994	VOGT et al.			
PA	KR 5,229,872	07/1993	MUMOLA			
PA	LR 6,046,792	04/2000	VAN DER WERF et al.			

FOREIGN PATENT DOCUMENTS

Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract	Translation Readily Available
				Enclosed	No
MR 98/38597	09/1998	WIPO	Thuren		
NR 98/33096	07/1998	WIPO	Sandstrom et al.		

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

PA	OR	Flagello et al., "Theory of high-NA imaging in homogeneous thin films," <i>J. Opt. Soc. Am. A</i> 13(1):53-64 (1996)			
PA	PR	Lopez et al., "Wave-plate polarizing beam splitter based on a form-birefringent multilayer grating," <i>Optics Letters</i> 23(20):1627-1629 (1998)			
PA	QR	Ferstl et al., "High-frequency gratings as polarization elements," <i>Part of the SPIE Conference on Micromachine Technology for Diffractive and Holographic Optics</i> 2879:138-146 (1999)			
PA	RR	Flagello et al., "Optical Lithography into the Millenium: Sensitivity to Aberrations, Vibration and Polarization," <i>SPIE The 25th Annual International Symposium on Microlithography</i> , February 27-March 3, 2000, Santa Clara, CA, pp. 1-12			
PA	SR	Switkes et al., "Immersion lithography at 157 nm," <i>J. Vac. Sci. Technol. B</i> 19(6):2353-2356 (2001)			
PA	TR	Bomzon et al., "Radially and azimuthally polarized beams generated by space-variant dielectric subwavelength gratings," <i>Optics Letters</i> 27(5):285-287 (2002)			
PA	UR	Mulkens et al., "157-nm Technology: Where are we Today?," <i>SPIE The 27th Annual Symposium on Microlithography</i> , March 3-8, 2002, Santa Clara, CA, pp. 1-11			

Examiner

Date Considered:

12-12-05

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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Examiner's Initials*		Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
<i>PA</i>	AR	6,288,840 B1	09/2001	PERKINS et al.			
<i>PA</i>	BR	6,262,796 B1	07/2001	LOOPSTRA et al.			
<i>PA</i>	CR	5,969,441	10/1999	LOOPSTRA et al.			
	DR						
	ER						
	FR						
	GR						
	HR						
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	JR						
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	MR						
	NR						
	OR						

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					Enclosed	No
	PR					
	QR					
	RR					
	SR					
	TR					
	UR					

OTHER (Including in this order: Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

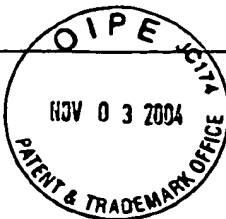
	VR					
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	AAR					
	BBR					
	CCR					

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Applicant: FLAGELLO et al.

Application No.: 10/786,473

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Examiner: Unassigned

Group Art Unit: 2872

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PA	AR	5,559,583	09/1996	Tanabe			
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PA	CR	2001/0022687 A1	09/2001	Takahashi et al.			
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	FR						
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	HR						
	IR						
	JR						
	KR						
	LR						

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		Document Number	Date MM/YYYY	Country	Inventor Name					
							Enclosed	No	Enclose	No
DA	MR	196 21 512 A1	12/1997	DE	Kley et al.		x			
	NR									

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

PA	OR	B. Stenkemp et al., "Grid polarizer for the visible spectral region," SPIE, p. 288-296, 1994.								
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